Notice of References Cited Application/Control No. 10/551,473 Examiner DANIEL WALSH Applicant(s)/Patent Under Reexamination PARKER, JOHN Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,070,240 A	05-2000	Xydis, Thomas G.	726/17
*	В	US-6,137,480 A	10-2000	Shintani, Peter	345/169
*	С	US-2001/0000814 A1	05-2001	Montgomery et al.	710/10
*	D	US-2002/0097417 A1	07-2002	Chang et al.	358/1.13
*	Е	US-2003/0025603 A1	02-2003	Smith, Edwin Derek	340/572.8
*	F	US-6,515,575 B1	02-2003	Kataoka, Kenji	340/5.8
*	G	US-2004/0123127 A1	06-2004	Teicher et al.	713/193
*	Н	US-2005/0235156 A1	10-2005	Chen, Magary	713/182
*	ı	US-2006/0005035 A1	01-2006	Coughlin, Michael E.	713/182
*	J	US-2006/0186199 A1	08-2006	Parker, John	235/382
*	K	US-2006/0265755 A1	11-2006	Liu, Ta-Wei	726/026
*	L	US-2007/0290036 A1	12-2007	Yang et al.	235/382
*	М	US-7,461,264 B2	12-2008	Chen, Magary	713/182

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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